

---

# Supplementary Material

---

## 1 Definition of Noise Models

On CIFAR-10 and CIFAR-100, following the traditional methods [3], we manually corrupt the training set according to the ground-truth transition matrices  $T$ , where  $T_{ij} = P(\tilde{y} = j|y = i)$  given that noisy label  $\tilde{y}$  is flipped from clean label  $y$ .

As described in [1], the Noise transition matrix supposes that the observed noisy label  $\tilde{y}$  is drawn independently from a corrupted distribution  $P(X, \tilde{Y})$ , where features are intact. Meanwhile, there exists a corruption process, transition from the latent clean label  $y$  to the observed noisy label  $\tilde{y}$ . Such a corruption process can be approximately modeled via noise transition matrix  $T$ , where  $T_{ij} = P(\tilde{y} = j|y = i)$ .

Specifically, we conduct experiments using three commonly used noisy types: 1) Symmetry flipping [4]; 2) Asymmetry flipping [4]; 3) Pair flipping [2].

### 1.1 The transition matrix $T$ of the Symmetry Flipping noise type

In the following,  $\varepsilon$  is the noise rate,  $C$  is number of classes, and the transition matrix  $T \in \mathbb{R}^{C \times C}$ .

$$T = \begin{bmatrix} 1 - \varepsilon & \frac{\varepsilon}{C-1} & \cdots & \frac{\varepsilon}{C-1} & \frac{\varepsilon}{C-1} \\ \frac{\varepsilon}{C-1} & 1 - \varepsilon & \cdots & \frac{\varepsilon}{C-1} & \frac{\varepsilon}{C-1} \\ \vdots & \vdots & \ddots & \vdots & \vdots \\ \frac{\varepsilon}{C-1} & \frac{\varepsilon}{C-1} & \cdots & 1 - \varepsilon & \frac{\varepsilon}{C-1} \\ \frac{\varepsilon}{C-1} & \frac{\varepsilon}{C-1} & \cdots & \frac{\varepsilon}{C-1} & 1 - \varepsilon \end{bmatrix} \quad (1)$$

### 1.2 The transition matrix $T$ of the Pair Flipping noise type

In the following,  $\varepsilon$  is the noise rate,  $C$  is number of classes, and the transition matrix  $T \in \mathbb{R}^{C \times C}$ .

$$T = \begin{bmatrix} 1 - \varepsilon & \varepsilon & 0 & \cdots & 0 \\ 0 & 1 - \varepsilon & \varepsilon & \cdots & 0 \\ \vdots & \vdots & \ddots & \vdots & \vdots \\ 0 & 0 & \cdots & 1 - \varepsilon & \varepsilon \\ \varepsilon & 0 & \cdots & 0 & 1 - \varepsilon \end{bmatrix} \quad (2)$$

### 1.3 The transition matrix $T$ of the Asymmetry Flipping noise type

The asymmetric label noise is designed to mimic some structure of the real mistakes for similar classes:  $TRUCK \rightarrow AUTOMOBILE$ ,  $BIRD \rightarrow AIRPLANE$ ,  $DEER \rightarrow HORSE$ ,  $CAT \leftrightarrow DOG$  [4]. Label transition matrix are parameterized by  $\varepsilon \in [0, 1]$  such that the true class and wrong class have probability of  $1 - \varepsilon$  and  $\varepsilon$ , respectively. An example of  $T$  used for CIFAR-10

dataset with  $\epsilon = 0.7$  is shown as follows.

$$T = \begin{bmatrix} 1 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 1 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0.3 & 0 & 0 & 0 & 0 & 0.7 & 0 & 0 \\ 0 & 0 & 0 & 0.3 & 0 & 0 & 0 & 0 & 0.7 & 0 \\ 0 & 0 & 0 & 0 & 1 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0.3 & 0.7 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0.7 & 0.3 & 0 & 0 & 0 \\ 0 & 0.7 & 0 & 0 & 0 & 0 & 0 & 0.3 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 1 \end{bmatrix} \quad (3)$$

## References

- [1] Bo Han, Quanming Yao, Tongliang Liu, Gang Niu, Ivor W Tsang, James T Kwok, and Masashi Sugiyama. A survey of label-noise representation learning: Past, present and future. *arXiv preprint arXiv:2011.04406*, 2020.
- [2] Lu Jiang, Zhengyuan Zhou, Thomas Leung, Li-Jia Li, and Li Fei-Fei. Mentornet: Learning data-driven curriculum for very deep neural networks on corrupted labels. In *International Conference on Machine Learning*, pages 2304–2313. PMLR, 2018.
- [3] Xuefeng Li, Tongliang Liu, Bo Han, Gang Niu, and Masashi Sugiyama. Provably end-to-end label-noise learning without anchor points. *arXiv preprint arXiv:2102.02400*, 2021.
- [4] Giorgio Patrini, Alessandro Rozza, Aditya Krishna Menon, Richard Nock, and Lizhen Qu. Making deep neural networks robust to label noise: A loss correction approach. In *Proceedings of the IEEE conference on computer vision and pattern recognition*, pages 1944–1952, 2017.